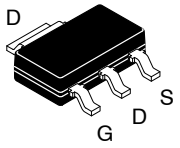
MOSFET – N-Channel, POWERTRENCH®

100 V, 3.2 A, 108 mΩ

FDT86106LZ

V_{DSS}	$R_{DS(ON)}$ MAX	I_D MAX
100 V	108 mΩ @ 10 V	3.2 A
	153 mΩ @ 4.5 V	



SOT−223
CASE 318H

General Description

This N−Channel logic Level MOSFETs are produced using **onsemi**'s advanced POWERTRENCH process that has been special tailored to minimize the on−state resistance and yet maintain superior switching performance. G−S zener has been added to enhance ESD voltage level.

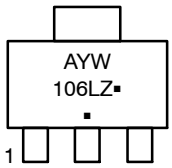
Features

- Max $r_{DS(on)}$ = 108 mΩ at V_{GS} = 10 V, I_D = 3.2 A
- Max $r_{DS(on)}$ = 153 mΩ at V_{GS} = 4.5 V, I_D = 2.7 A
- High Performance Trench Technology for Extremely Low $r_{DS(on)}$
- High Power and Current Handling Capability in a Widely Used Surface Mount Package
- HBM ESD Protection Level > 3 kV Typical (Note 4)
- 100% UIL Tested
- This Device is Pb−Free, Halide Free and is RoHS Compliant

Applications

- DC − DC Conversion

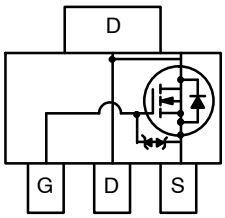
MARKING DIAGRAM



A = Specific Device Code
Y = Date Code
W = Work Week
106LZ = Specific Device Code
▪ = Pb−Free Package

(Note: Microdot may be in either location)

PINOUT



MOSFET MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Symbol	Parameter		Ratings	Unit
V_{DS}	Drain−Source Voltage		100	V
V_{GS}	Gate−Source Voltage		±20	V
I_D	Drain Current	− Continuous T_A = 25°C (Note 1a.)	3.2	A
		− Pulsed	12	
E_{AS}	Single Pulse Avalanche Energy (Note 3)		12	mJ
P_D	Power Dissipation	T_A = 25°C (Note 1a.)	2.2	W
		T_A = 25°C (Note 1b.)	1.0	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		−55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	12	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a.)	55	°C/W

ORDERING INFORMATION

Device	Package	Shipping†
FDT86106LZ	106LZ	4000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

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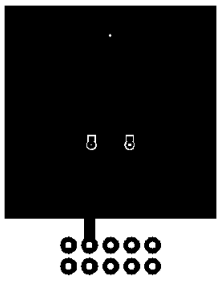
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V	100	–	–	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C	–	71	–	mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 80 V, V_{GS} = 0 V	–	–	1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20 V, V_{DS} = 0 V	–	–	±10	μA
ON CHARACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	1.0	1.5	2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25°C	–	–5	–	mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 3.2 A V_{GS} = 4.5 V, I_D = 2.7 A, V_{GS} = 10 V, I_D = 3.2 A, T_J = 125°C	– – –	80 100 140	108 153 189	mΩ
g_{FS}	Forward Transconductance	V_{DS} = 10 V, I_D = 3.2 A	–	8	–	S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = 50 V, V_{GS} = 0 V, f = 1 MHz	–	234	315	pF
C_{oss}	Output Capacitance		–	46	65	pF
C_{rss}	Reverse Transfer Capacitance		–	3.1	5	pF
SWITCHING CHARACTERISTICS						
$t_{d(on)}$	Turn–On Delay Time	V_{DD} = 50 V, I_D = 3.2 A, V_{GS} = 10 V, R_{GEN} = 6 Ω	–	3.8	10	ns
t_r	Rise Time		–	1.3	10	ns
$t_{d(off)}$	Turn–Off Delay Time		–	10	20	ns
t_f	Fall Time		–	1.5	10	ns
Q_g	Total Gate Charge	V_{GS} = 0 V to 10 V, V_{DD} = 50 V, I_D = 3.2 A	–	4.3	7	nC
Q_g	Total Gate Charge	V_{GS} = 0 V to 5 V, V_{DD} = 50 V, I_D = 3.2 A	–	2.4	4	nC
Q_{gs}	Gate to Source Gate Charge	V_{DD} = 50 V, I_D = 3.2 A	–	0.7	–	nC
Q_{gd}	Gate to Drain “Miller” Charge		–	0.9	–	nC
DRAIN–SOURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 3.2 A (Note 2) V_{GS} = 0 V, I_S = 1 A (Note 2)	– –	0.86 0.77	1.3 1.2	V
t_{rr}	Reverse Recovery Time	I_F = 3.2 A, di/dt = 100 A/s	–	31	49	ns
Q_{rr}	Reverse Recovery Charge		–	21	34	nC

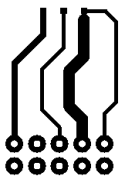
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTES:

1. $R_{\theta JA}$ is the sum of the junction–to–case and case–to–ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user’s board design.



a. 55°C/W when mounted on a 1 in^2 pad of 2 oz copper.



b. 118°C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0 %.
3. Starting T_J = 25°C, L = 1 mH, I_{AS} = 5 A, V_{DD} = 90 V, V_{GS} = 10 V.
4. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

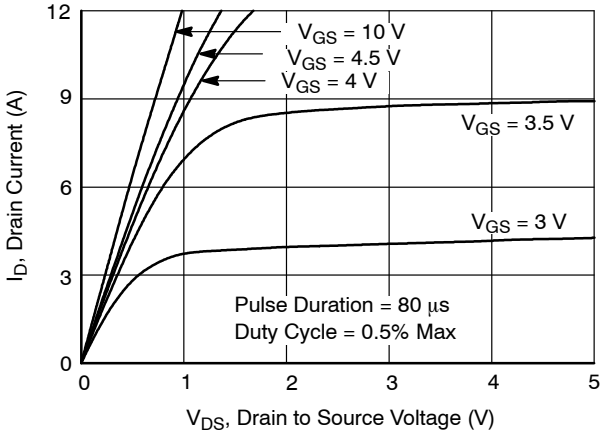


Figure 1. On−Region Characteristics

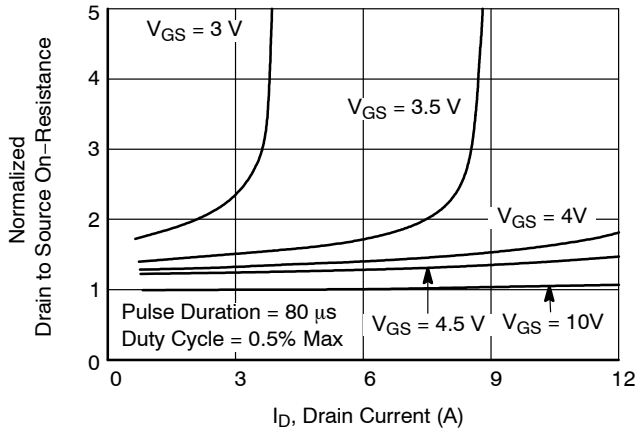


Figure 2. Normalized On−Resistance vs. Drain Current and Gate Voltage

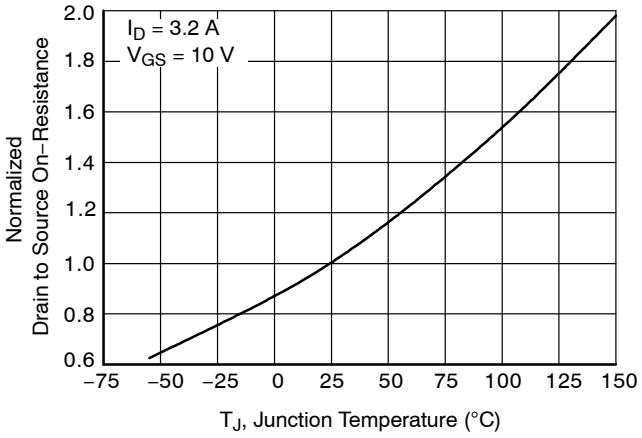


Figure 3. Normalized On−Resistance vs. Junction Temperature

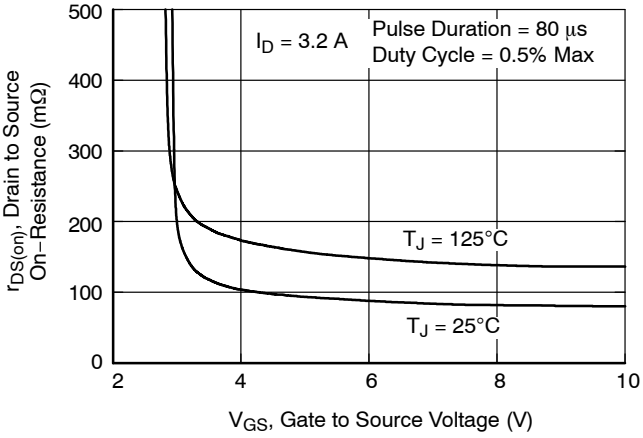


Figure 4. On−Resistance vs. Gate to Source Voltage

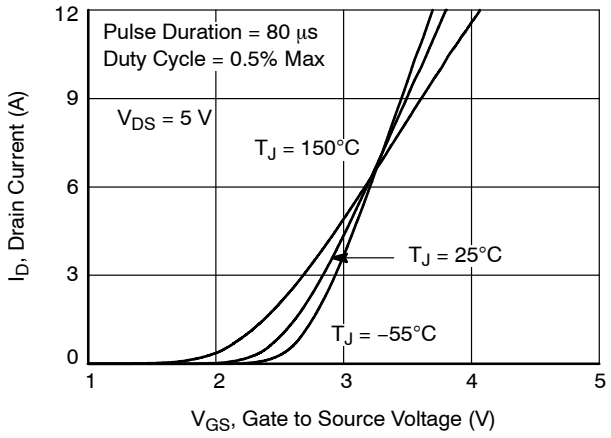


Figure 5. Transfer Characteristics

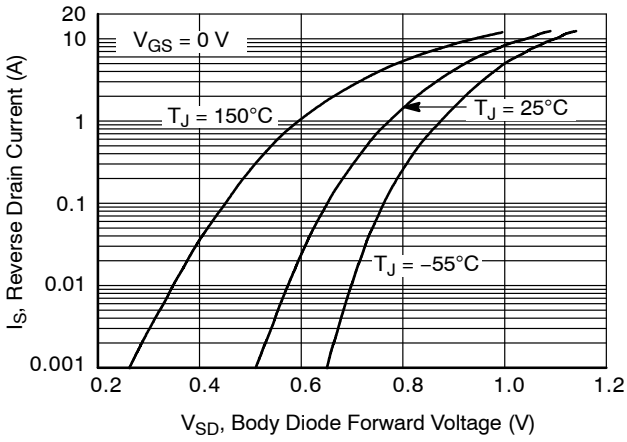


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

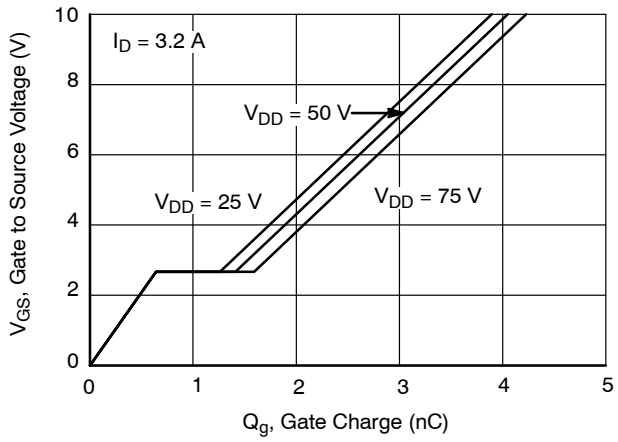


Figure 7. Gate Charge Characteristics

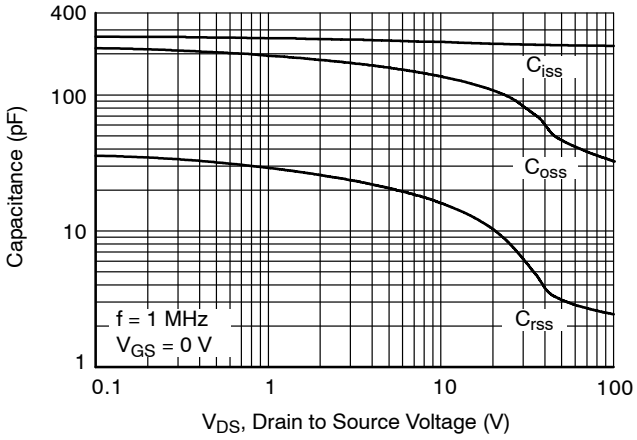


Figure 8. Capacitance vs. Drain to Source Voltage

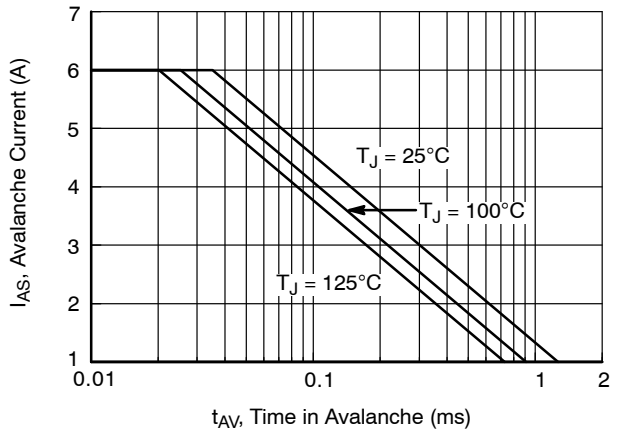


Figure 9. Unclamped Inductive Switching Capability

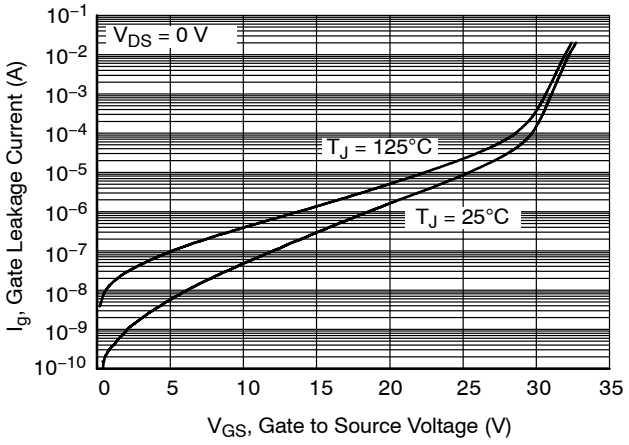


Figure 10. Gate Leakage Current vs. Gate to Source Voltage

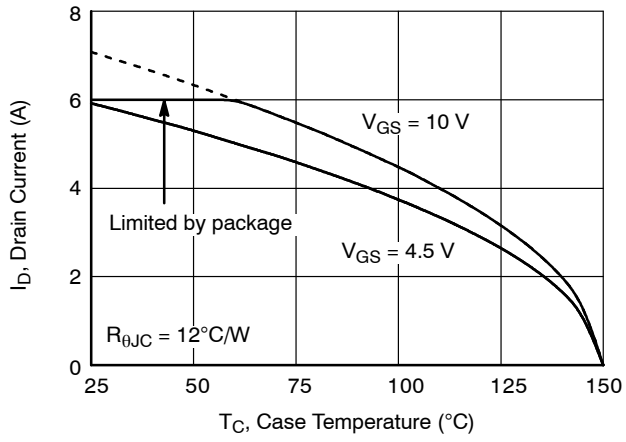


Figure 11. Maximum Continuous Drain Current vs. Case temperature

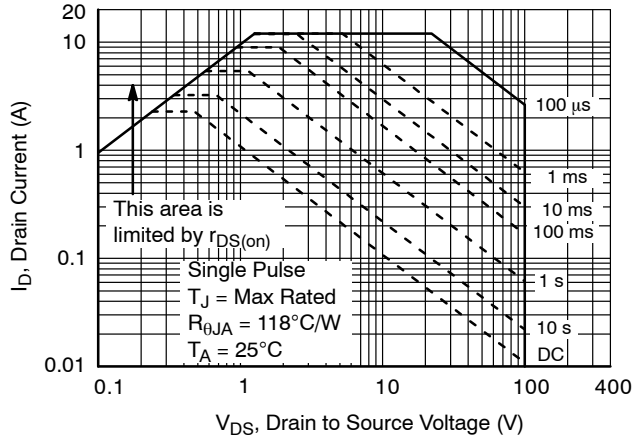


Figure 12. Forward Bias Safe Operating Area

TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

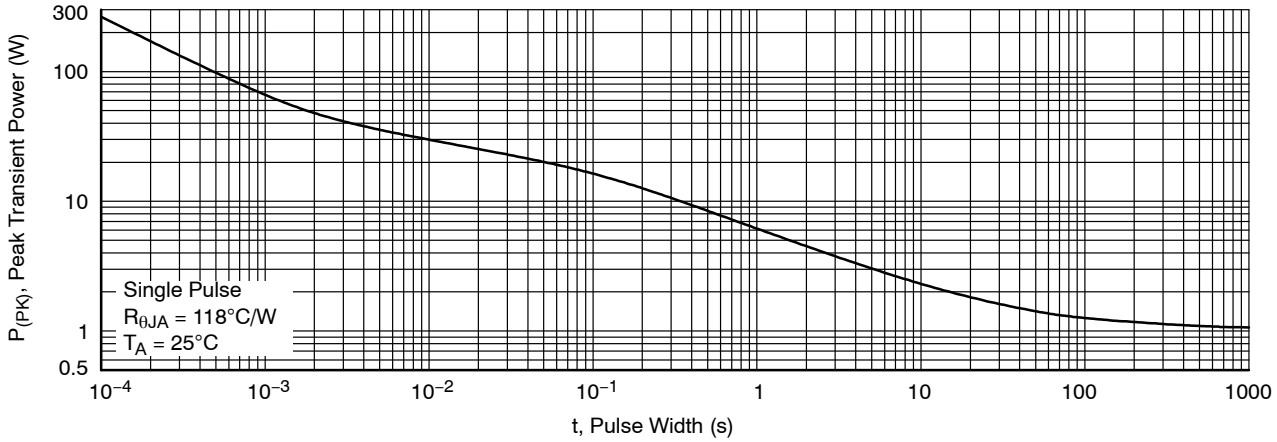


Figure 13. Single Pulse Maximum Power Dissipation

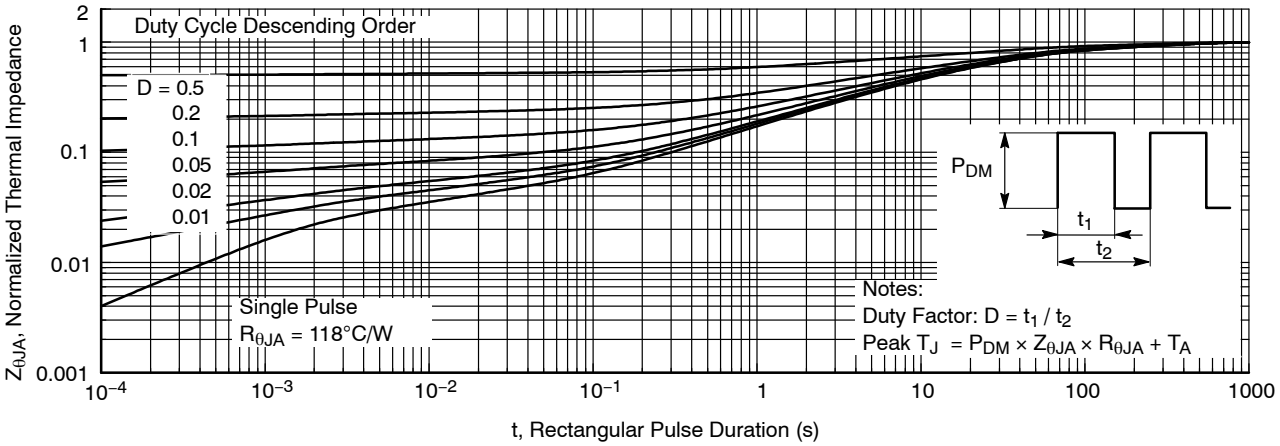


Figure 14. Junction−to−Ambient Transient Thermal Response Curve

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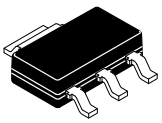
MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

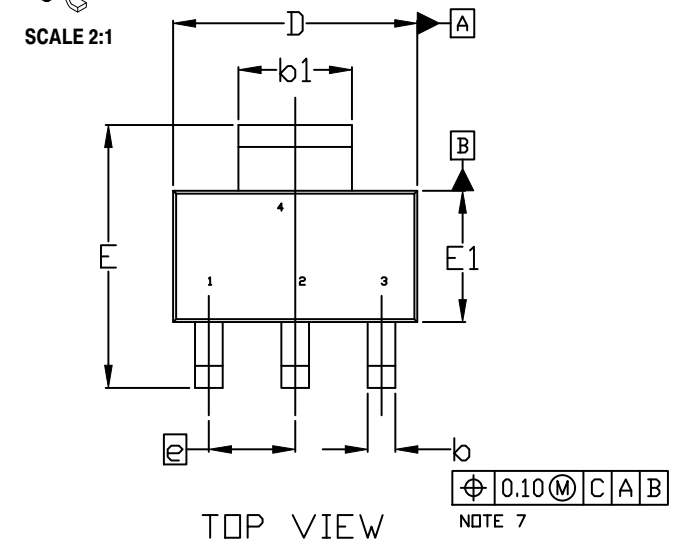
ON Semiconductor®

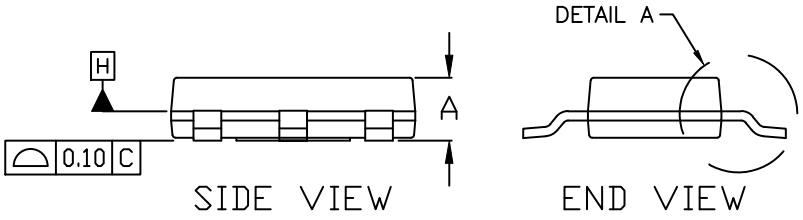
SOT−223
CASE 318H
ISSUE B

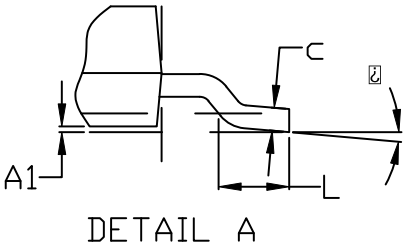
DATE 13 MAY 2020



SCALE 2:1

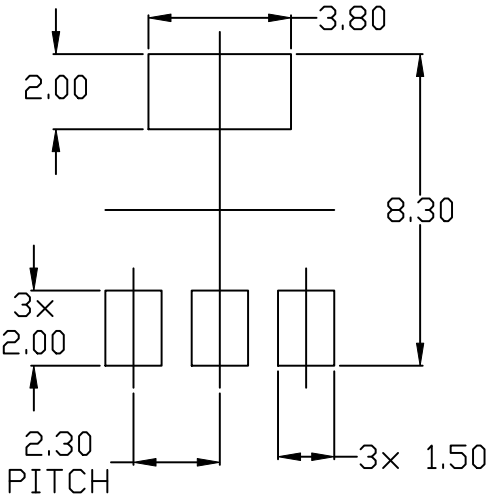






NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSIONS D & E1 ARE DETERMINED AT DATUM H. DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. SHALL NOT EXCEED 0.23mm PER SIDE.
4. LEAD DIMENSIONS b AND b1 DO NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBBAR PROTRUSION IS 0.08mm PER SIDE.
5. DATUMS A AND B ARE DETERMINED AT DATUM H.
6. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT OF THE PACKAGE BODY.
7. POSITIONAL TOLERANCE APPLIES TO DIMENSIONS b AND b1.

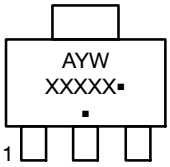
	MILLIMETERS		
DIM	MIN.	NOM.	MAX.
A	---	---	1.80
A1	0.02	0.06	0.11
b	0.60	0.74	0.88
b1	2.90	3.00	3.10
c	0.24	---	0.35
D	6.30	6.50	6.70
E	6.70	7.00	7.30
E1	3.30	3.50	3.70
e	2.30 BSC		
L	0.25	---	---
θ	0°	---	10°



RECOMMENDED MOUNTING FOOTPRINT

* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



A = Assembly Location
Y = Year
W = Work Week
XXXXX = Specific Device Code
▪ = Pb−Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

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